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ZAMANBYE-3172/70
16 October 1970Copy 1 MEMORANDUM FOR: Executive Director, NPIC *A*SUBJECT : Status of PI Comparison Test of
Simulated Electro-Optical Imagery

1. In cooperation with OSP/DDS&T, the NPIC team, chaired by [redacted] is making satisfactory progress in designing and conducting the PI Comparison Test of Simulated Electro-Optical Imagery. The test will consist of ranking several different quality simulated Electro-Optical Images and the best KH-8 image to determine what Electro-Optical System parameters are required to produce imagery better or equal to the best KH-8 imagery.

2. The schedule for completion of this project is as follows:

- a. 22-23 October - Comparison tests of the KH-8 "contact" image with its enlarged version and of the "contact" EOI simulated material with its reduced version. The "contact" materials will not be used in the final PI comparison tests because of the large differences in scale; however, before the PI testing is attempted it must be determined that neither of the equal scale materials has been degraded through the photographic process.
- b. 26-30 October - PI testing of the equal scale best KH-8 and simulated EOI images.
- c. 2-6 November - Writing of final report.

[redacted]
Chief, Planning, Programming & Budgeting Staff
NPIC

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